

RAJIV GANDHI INSTITUTE OF PETROLEUM TECHNOLOGY, JAIS, AMETHI

CORRIGENDUM-1

Date: 15.11.2019

Please refer to E-Tender on RGIPT/JAIS/E-OPN/LAB/2019-20/36 in rgipt.euniwizarde.com portal & Institute Website for the procurement of High Resolution Transmission Electron Microscope (HRTEM).

Corrections/Addendum to HRTEM Technical Specifications

Point No.	Item	Modifications (after Pre-bid)	Before Pre-bid
4.	Magnification	HRTEM magnification: 100 x to 10 ⁶ x or better	1,50,000x or better
10.	Probe Corrector 200 kV	Atomic characterization Probe Corrector should give sub-Angstrom STEM imaging resolution from 30 kV to 200 kV. Control of the corrector should be embedded in the TEM software (including routines for aligning the corrector). 78 pm @ 200kV, 110 pm @60kV, 160 pm@ 30kV	Atomic characterization Probe Corrector should give sub-Angstrom STEM imaging resolution from 30 kV to 200 kV. Control of the corrector should be embedded in the TEM software (including routines for aligning the corrector).
13	Sample Holder and Goniometer	(d) The specimen stage must have a direct position measurement system that is free/negligible (not compromising with image quality) of backlash, orthogonal hysteresis, and run-on.	(d) The specimen stage must have a direct position measurement system that is free of backlash, orthogonal hysteresis, and run-on.
14	Imaging & Data recording system	(c) 3-D reconstruction/tomography commercial kit including necessary software. The system must include qualitative and quantitative elemental analysis, X-Ray mapping, capability for spectrum analysis, digital control of the beam for composition profile & Drift correction facility. It may also include Phase-mapping, peak-deconvolution. Element to phase map and phase to element map.	(c) 3-D reconstruction/tomography kit including necessary software. The system must include qualitative and quantitative elemental analysis, X-Ray mapping, capability for spectrum analysis, digital control of the beam for composition profile. Phase-mapping, peak-deconvolution. Element to phase map and phase to element map. Drift correction facility.
16	STEM	(b) Better Signal to Noise: Single electron sensitivity up to 1-1.25nA (at 200kV) (c) Ability to acquire images- HAADF, BF, DF/ Back scattered electron simultaneously.	(b) Better Signal to Noise: Single electron sensitivity up to 1.25nA (at 200kV) (c) Ability to acquire images- HAADF, BF, DF/Back scattered electron, simultaneously.

Ameg

M.S. [Signature]

17	EDS	The EDS detector solid angle should be ≥ 0.70 srad or better at all tilt angles. The EDS must incorporate one or more silicon Drift detectors	The EDS detector solid angle should be ≥ 0.97 srad or better at all tilt angles. The EDS must incorporate more than one silicon Drift detectors
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N.B.: A marking system will be used to evaluate the bids. The bid that receives more than the threshold mark fixed by the purchase committee will be considered further for finance bid.

The last date to receive the bids is extended till 28th Nov 2019 3pm & the Opening of Techno- Commercial bid will be at 4pm.



Dr. U. Ojha

Chairman, Institute Equipment Purchase Committee

